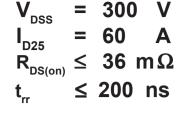


PolarHT[™] HiPerFET IXFR 102N30P Power MOSFET

(Electrically Isolated Back Surface)

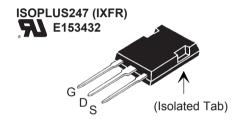
N-Channel Enhancement Mode Fast Intrinsic Diode Avalanche Rated





Symbol	Test Conditions	Maximum F	Maximum Ratings		
V _{DSS}	T _J = 25° C to 150° C	300	V		
$\mathbf{V}_{\mathtt{DGR}}$	$T_J = 25^{\circ} \text{C to } 150^{\circ} \text{C}; R_{GS} = 1 \text{ M}\Omega$	300	V		
V _{GS}	Continuous	±20	V		
V _{GSM}	Transient	±30	V		
I _{D25}	T _c =25°C	60	Α		
I _{DM}	$T_{\rm C}$ = 25° C, pulse width limited by $T_{\rm JM}$	250	Α		
I _{AR}	T _c =25°C	60	Α		
E_{AR}	T _C =25°C	60	mJ		
E _{as}	$T_{c} = 25^{\circ}C$	2.5	J		
dv/dt	$I_{s} \le I_{DM}$, di/dt ≤ 100 A/ μs , $V_{DD} \le V_{DSS}$, $T_{J} \le 150^{\circ}$ C, $R_{G} = 4 \Omega$	10	V/ns		
P _D	T _c =25°C	250	W		
T _J T _{JM} T _{stg}		-55 +150 150 -55 +150	°C °C °C		
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C		
V _{ISOL}	50/60 Hz, RMS, 1 minute	2500	V~		
F _c	Mounting force	22130/529	N/lb		
Weight		5	g		

			Ch Min.	aracteristic Values Typ. Max.		
BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		300			V
$V_{\rm GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 4 \text{ mA}$		2.5		5.0	V
GSS	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$				±200	nA
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 125° C			25 250	μA μA
R _{DS(on)}	V_{GS} = 10 V, I_{D} = 51 A Pulse test, t ≤300 µs, duty	cycle d ≤ 2 %			36	mΩ



G = Gate D = Drain S = Source

Features

- Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- ¹ International standard packages
- Unclamped Inductive Switching (UIS) rated
- ¹ Low package inductance
 - easy to drive and to protect

Advantages

- ^I Easy to mount
- Space savings
- High power density

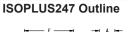


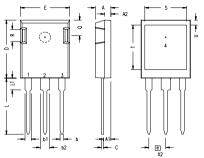
Symbo	ol	Test Conditions $(T_{_J} = 25^{\circ} \text{C}$	Characteristic Values [] = 25° C, unless otherwise specified) Min. Typ. Max.		
g _{fs}		V_{DS} = 10 V; I_{D} = 51 A, pulse test	45	57	S
C _{iss})			7500	pF
C _{oss}	}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		1150	pF
\mathbf{C}_{rss}	J			230	pF
t _{d(on)})			30	ns
t _r		$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = 51 \text{ A}$		28	ns
$\mathbf{t}_{d(off)}$		$R_{\rm G}$ = 3.3 Ω (External)		130	ns
t _f	J			30	ns
$\mathbf{Q}_{\mathrm{g(on)}}$)			224	nC
\mathbf{Q}_{gs}	}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}_{DSS}, I_{D} = 51 \text{ A}$		50	nC
\mathbf{Q}_{gd}	J			110	nC
R _{thJC}					0.5 °C/W
$\mathbf{R}_{\mathrm{thCS}}$				0.15	° C/W

Source-Drain Diode

Characteristic Values (T₁ = 25°C, unless otherwise specified)

Symbol	Test Conditions	Min.	Тур.	Max.	
I _s	$V_{GS} = 0 V$			102	Α
I _{SM}	Repetitive			250	Α
V _{SD}	$I_F = I_S, V_{GS} = 0 \text{ V},$ Pulse test, t \leq 300 μ s, duty cycle d \leq 2 %			1.5	V
$\left\{ egin{array}{c} \mathbf{t}_{rr} \\ \mathbf{Q}_{RM} \\ \mathbf{I}_{RM} \end{array} \right\}$	$I_F = 25 \text{ A}, -di/dt = 100 \text{ A/}\mu\text{s}$ $V_R = 100 \text{ V}, V_{GS} = 0 \text{ V}$		0.8	200	ns μC Α





MYZ	L INCH	INCHES		MILLIMETERS		
2114	MIN	MAX	MIN	MAX		
Α	.190	.205	4.83	5.21		
A1	.090	.100	2.29	2.54		
A2	.075	.085	1.91	2.16		
Ь	.045	.055	1.14	1.40		
b1	.075	.084	1.91	2.13		
b2	.115	.123	2.92	3.12		
С	.024	.031	0.61	0.80		
D	.819	.840	20.80	21.34		
E	.620	.635	15.75	16.13		
е	.215 BSC		5.45 BSC			
L	.780	.800	19.81	20.32		
L1	.150	.170	3.81	4.32		
Q	.220	.244	5.59	6.20		
R	.170	.190	4.32	4.83		
S	.520	.540	13.21	13.72		
Т	.620	.640	15.75	16.26		
U	.065	.080	1.65	2.03		

1 - GATE 2 - DRAIN (COLLECTOR) 3 - SOURCE (EMITTER) 4 - NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.



Fig. 1. Output Characteristics

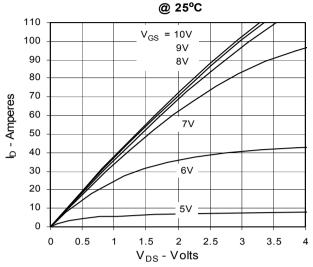


Fig. 3. Output Characteristics @ 125°C

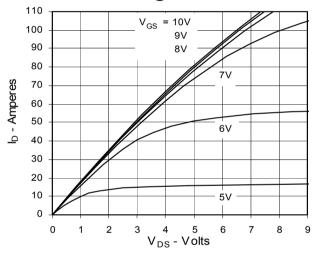


Fig. 5. R_{DS(on)} Normalized to

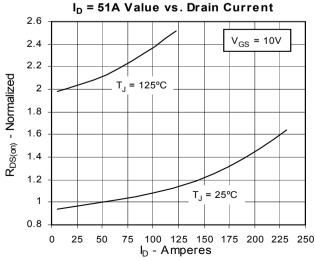


Fig. 2. Extended Output Characteristics @ 25°C

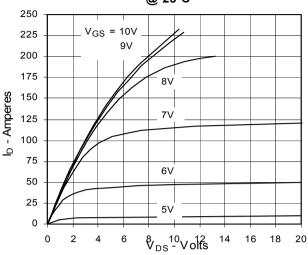


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 51A$ Value vs. Junction Temperature

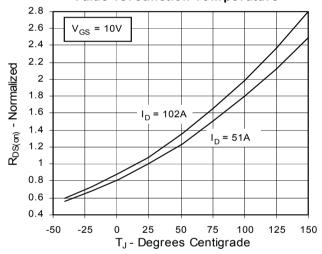


Fig. 6. Drain Current vs. Case
Temperature

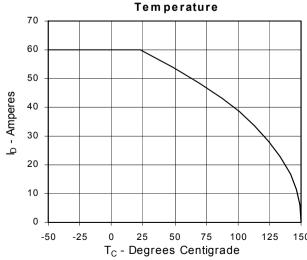


Fig. 7. Input Admittance

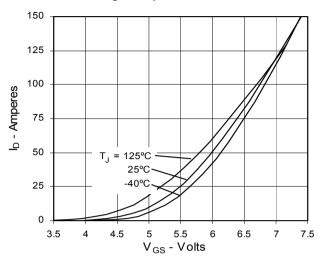


Fig. 9. Source Current vs. Source-To-Drain Voltage

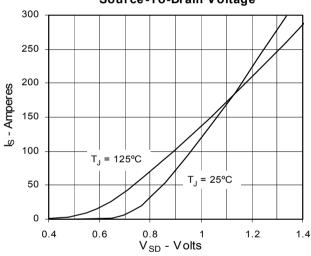


Fig. 11. Capacitance

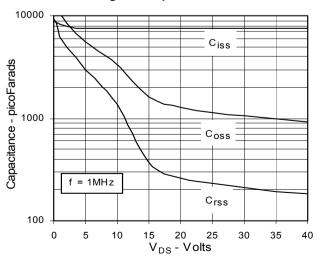


Fig. 8. Transconductance

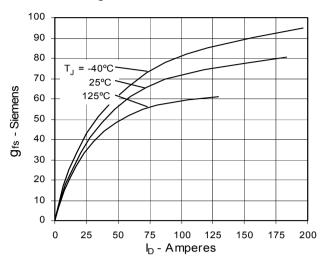


Fig. 10. Gate Charge

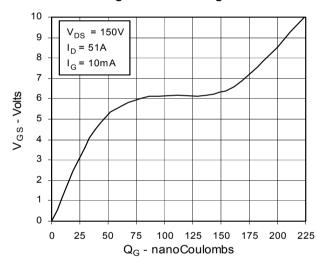
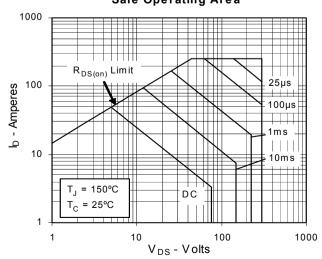


Fig. 12. Forward-Bias Safe Operating Area





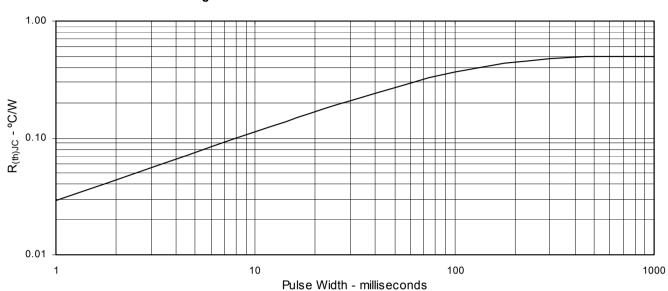


Fig. 13. Maximum Transient Thermal Resistance

